

Electronic Supplementary Information

Table ESI-1 Ratio of green (500-600 nm) to blue (400-500 nm) integrated intensity for select spectra.

Spectrum	Film	Green/Blue ratio
Figure 5-I dashed blue	Annealed 1-1 blend	0.30
Figure 5-II dashed black	Annealed 3-1 blend	0.56
Figure 5-III dashed green	Annealed 5-1 blend	0.69
Figure 5-IV dashed orange	Annealed 8-1 blend	0.74
Figure 5-V dashed red	Annealed PFO	2.44
Figure 6 blue	PFO re-annealed with PPE on top	0.60
Figure 6 green	Annealed PFO	1.33
Figure 6 red	Re-annealed PFO	1.63

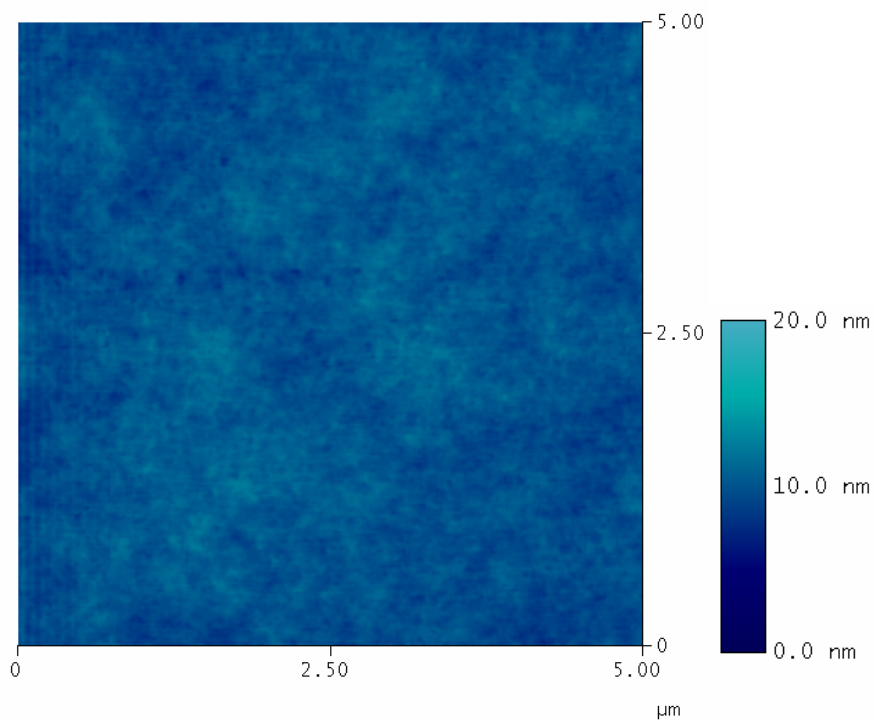


Figure ESI-1: AFM image of thin film cast from 1-1 blend.

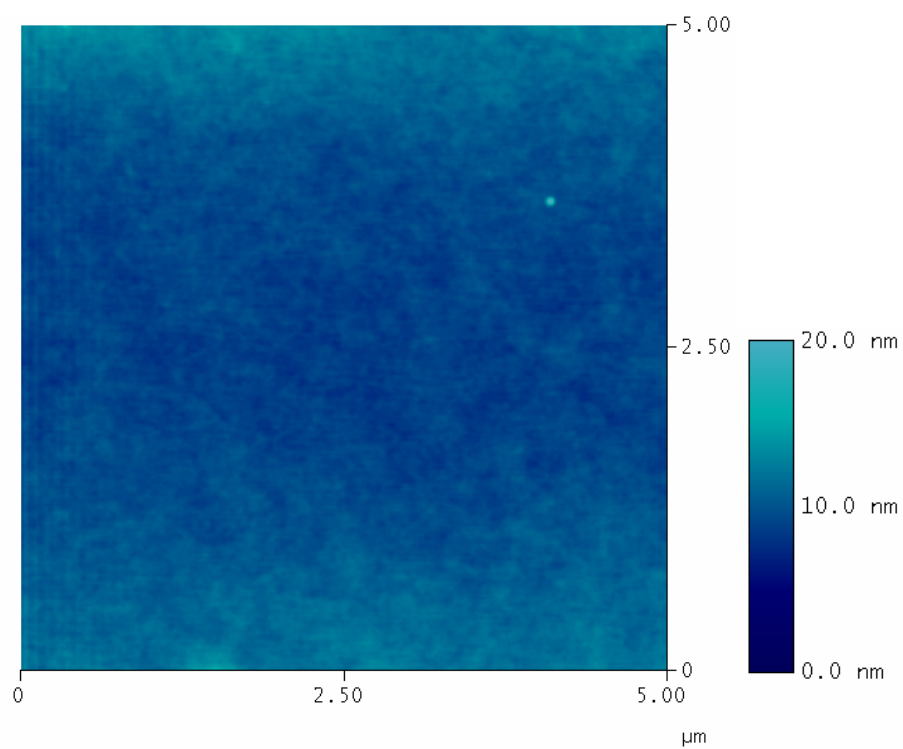


Figure ESI-2: AFM image of thin film cast from 3-1 blend.

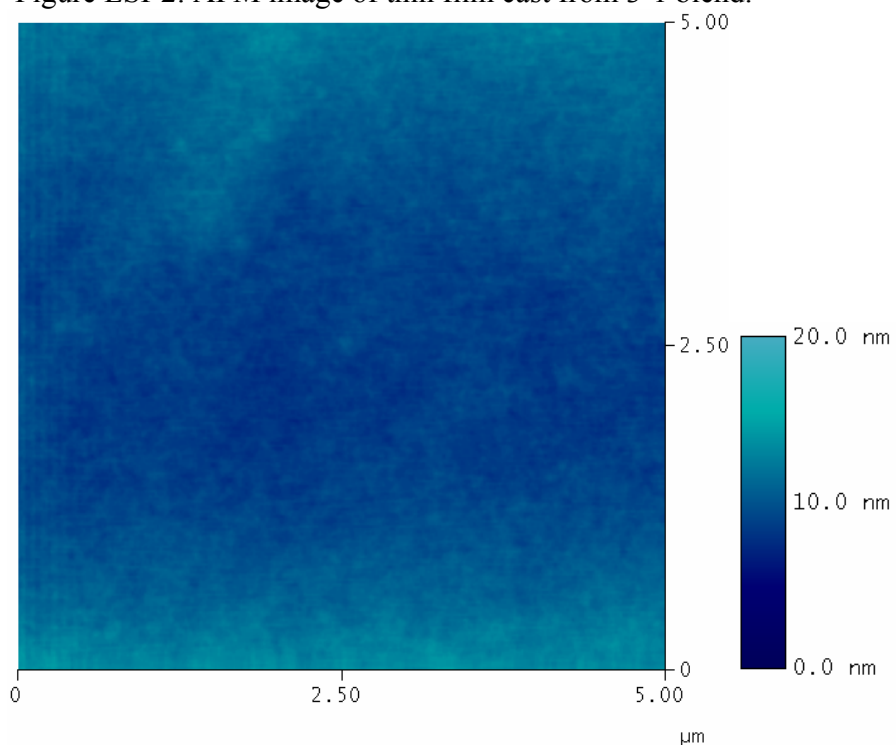


Figure ESI-3: AFM image of thin film cast from 5-1 blend.

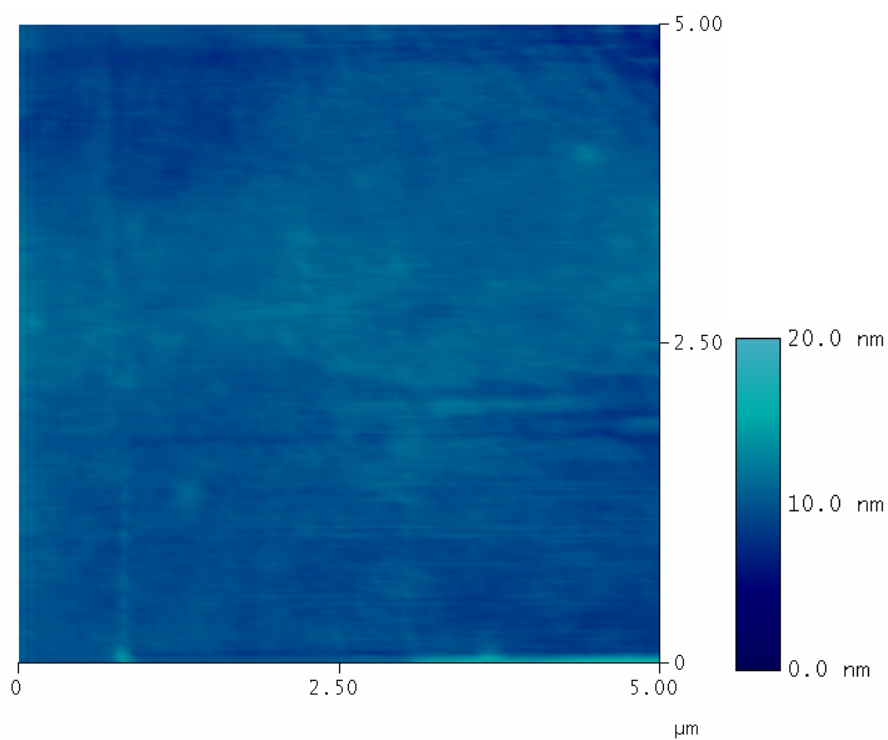


Figure ESI-4: AFM image of thin film cast from 8-1 blend.

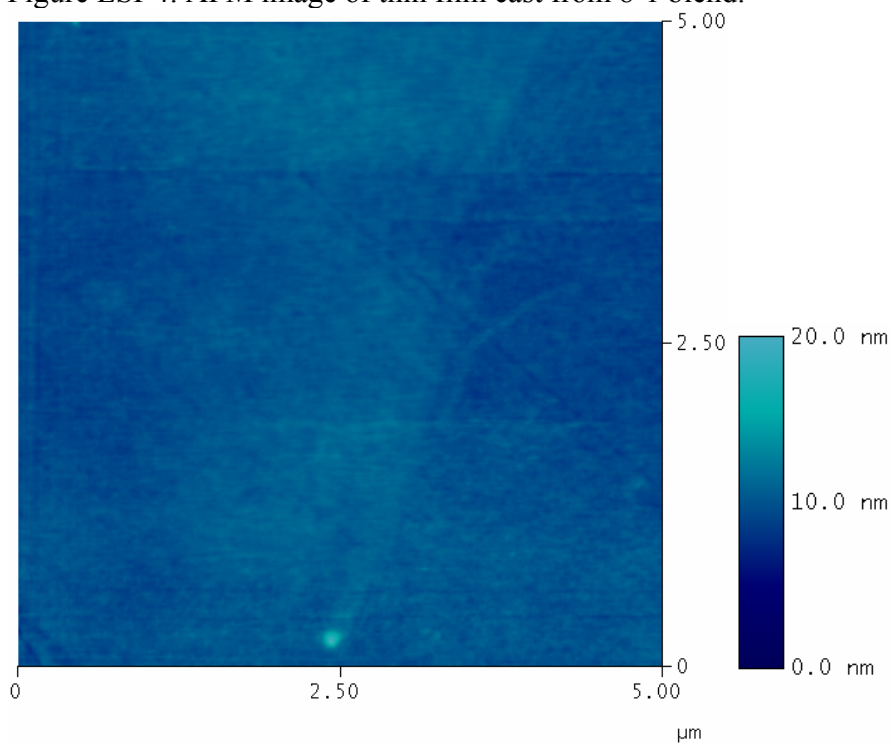


Figure ESI-5: AFM image of thin film cast from PFO.

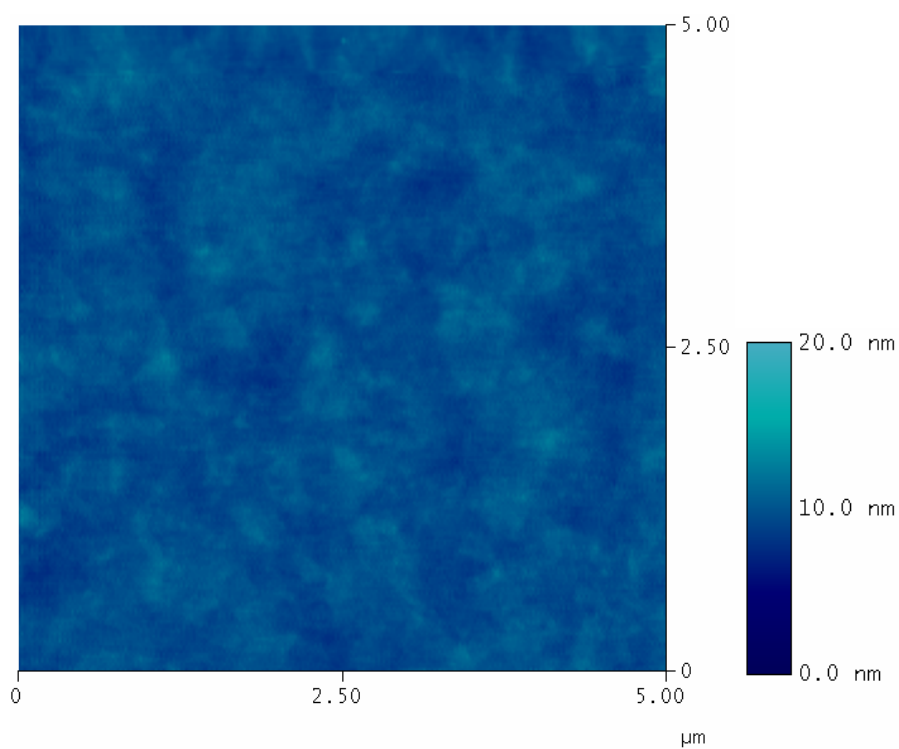


Figure ESI-6: AFM image of thin film cast from 1-1 blend after annealing in air for 60 minutes.

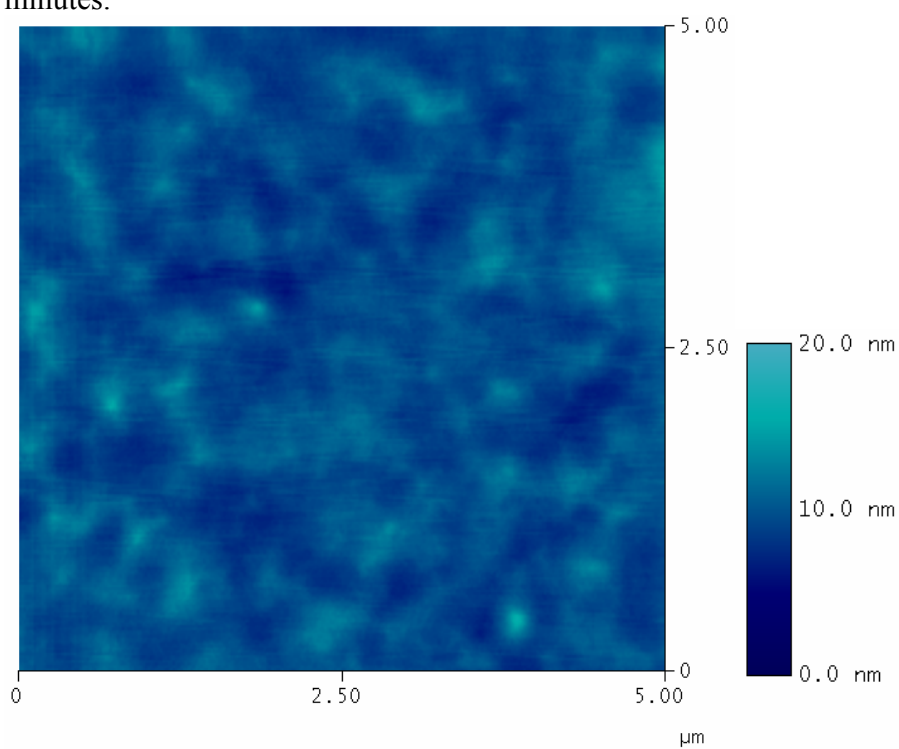


Figure ESI-7: AFM image of thin film cast from 3-1 blend after annealing in air for 60 minutes.

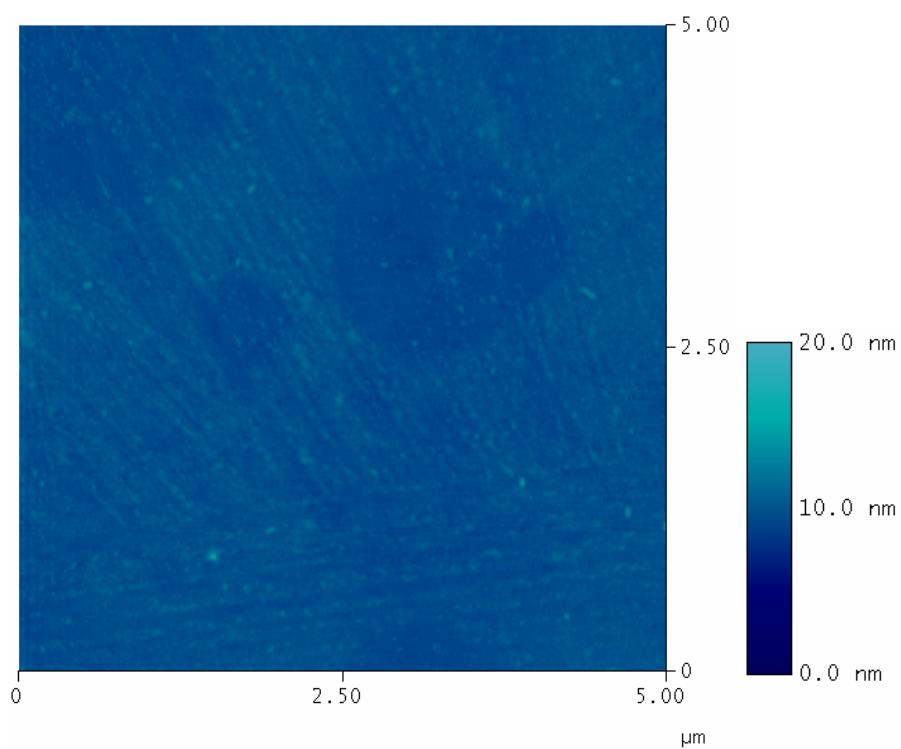


Figure ESI-8: AFM image of thin film cast from 5-1 blend after annealing in air for 60 minutes.

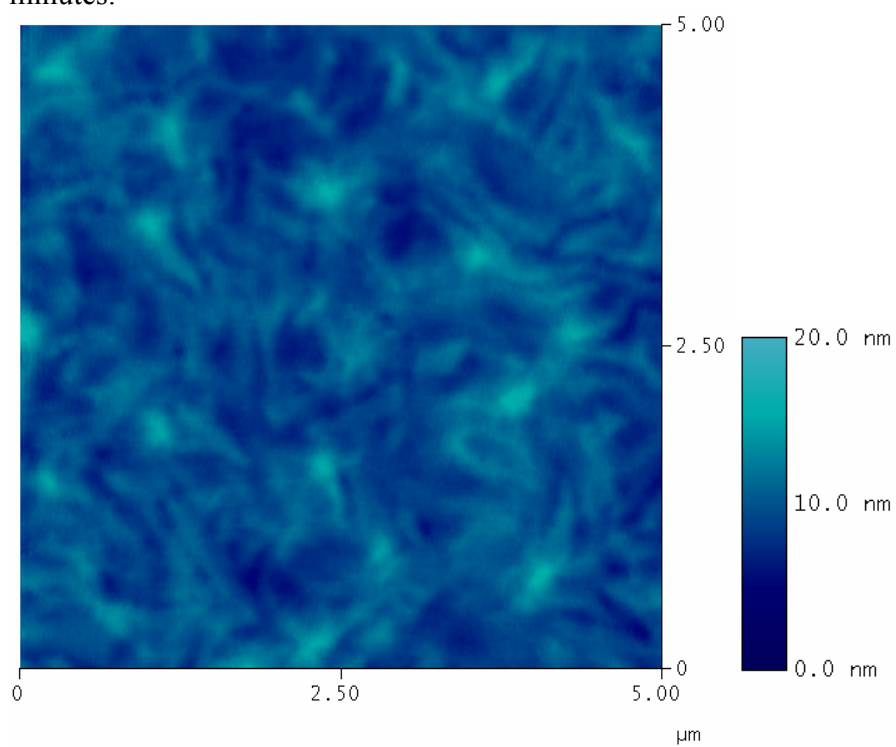


Figure ESI-9: AFM image of thin film cast from 8-1 blend after annealing in air for 60 minutes.

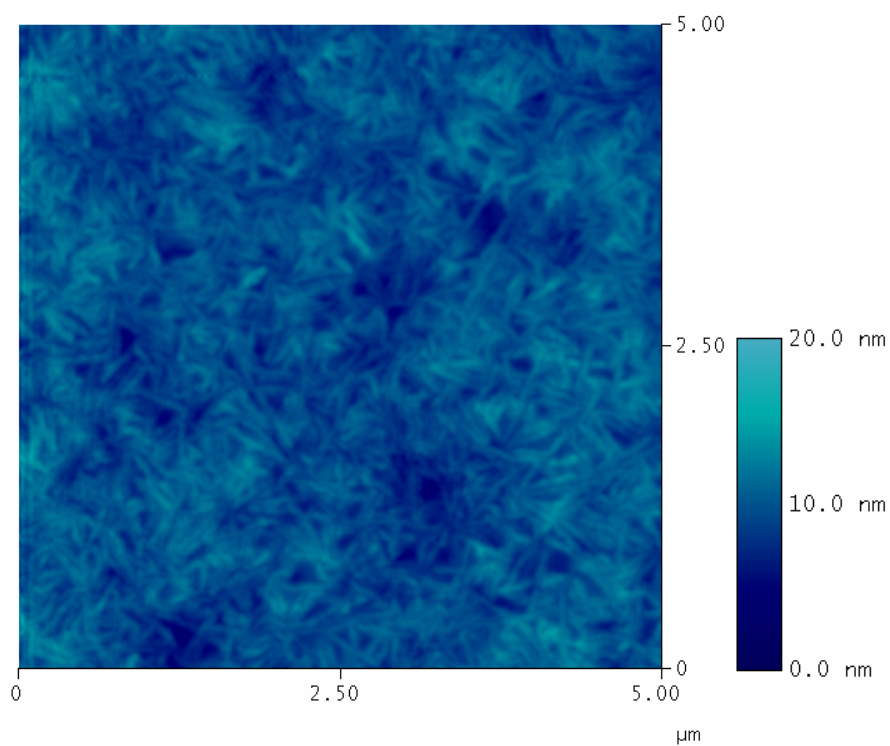


Figure ESI-10: AFM image of thin film cast from PFO after annealing in air for 60 minutes.



Figure ESI-11: PLM image of thin film cast from 1-1 blend.

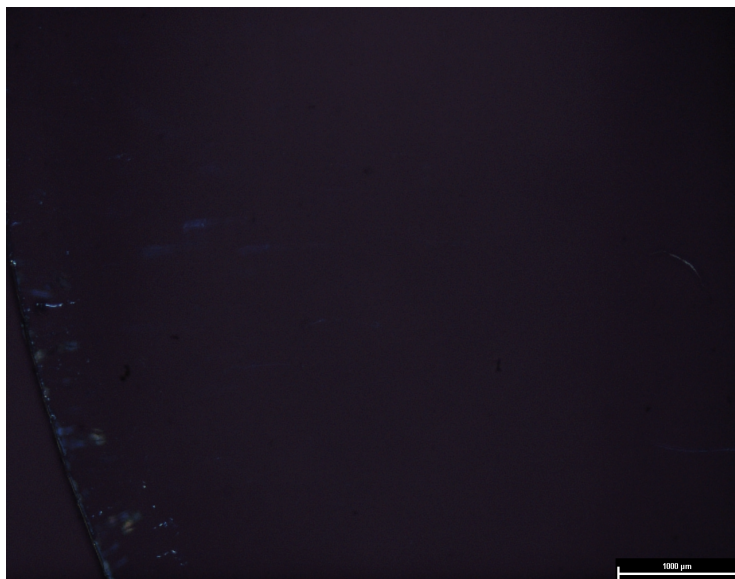


Figure ESI-12: PLM image of thin film cast from 3-1 blend.

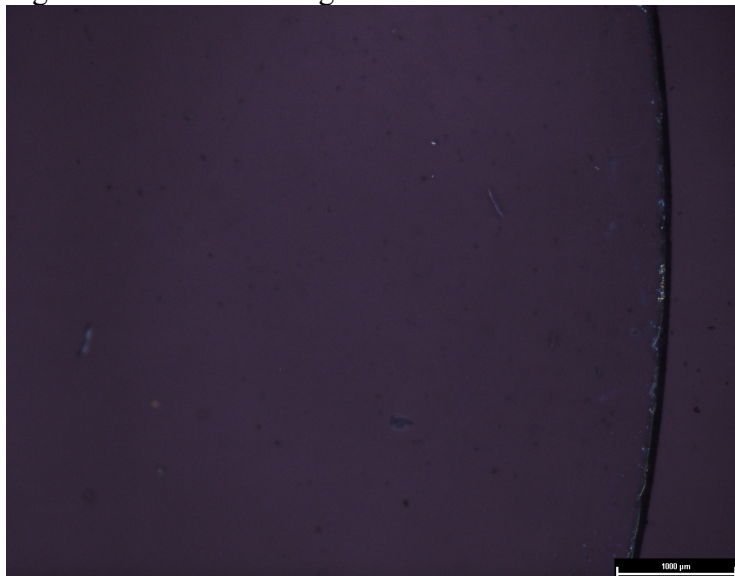


Figure ESI-13: PLM image of thin film cast from 5-1 blend.

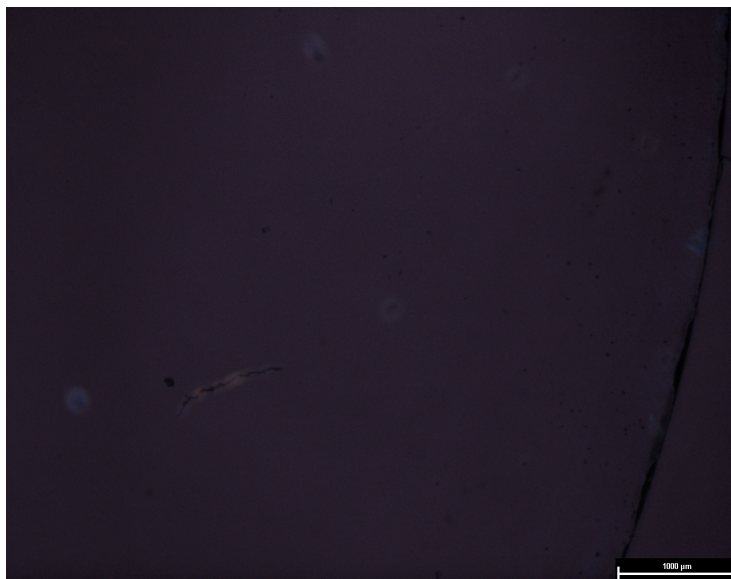


Figure ESI-14: PLM image of thin film cast from 8-1 blend.

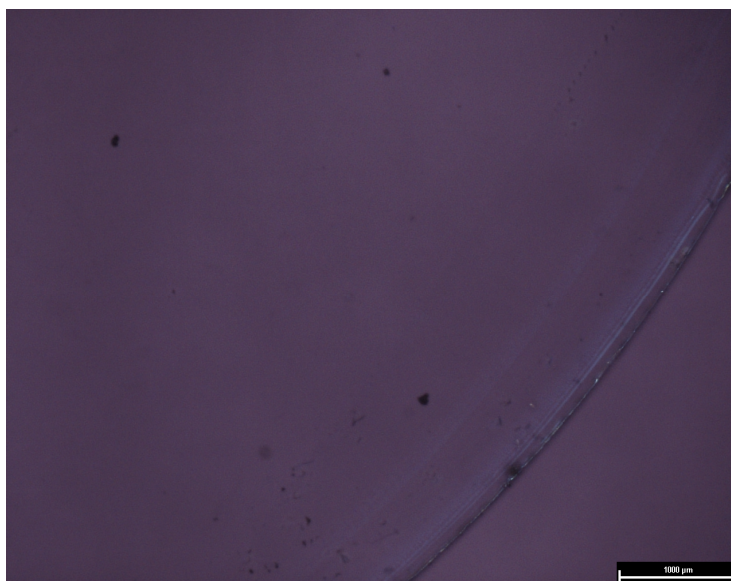


Figure ESI-15: PLM image of thin film cast from PFO.

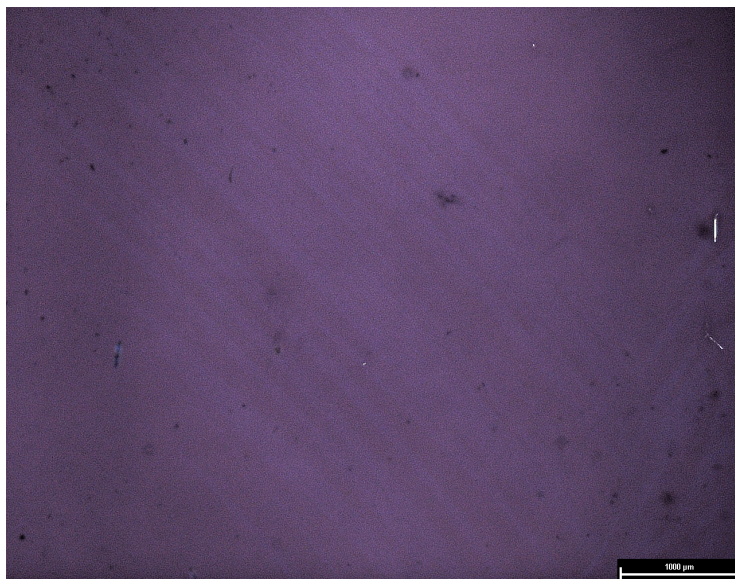


Figure ESI-16: PLM image of thin film cast from 1-1 blend after annealing in air for 60 minutes.

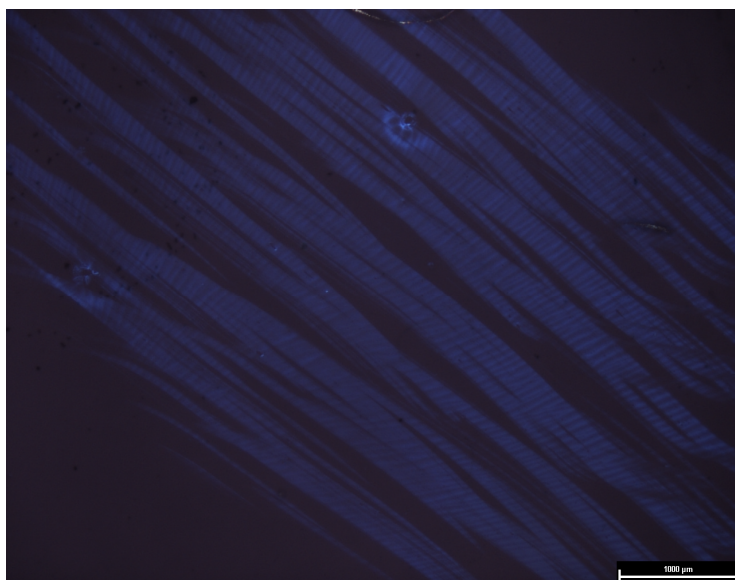


Figure ESI-17: PLM image of thin film cast from 3-1 blend after annealing in air for 60 minutes.



Figure ESI-18: PLM image of thin film cast from 5-1 blend after annealing in air for 60 minutes.

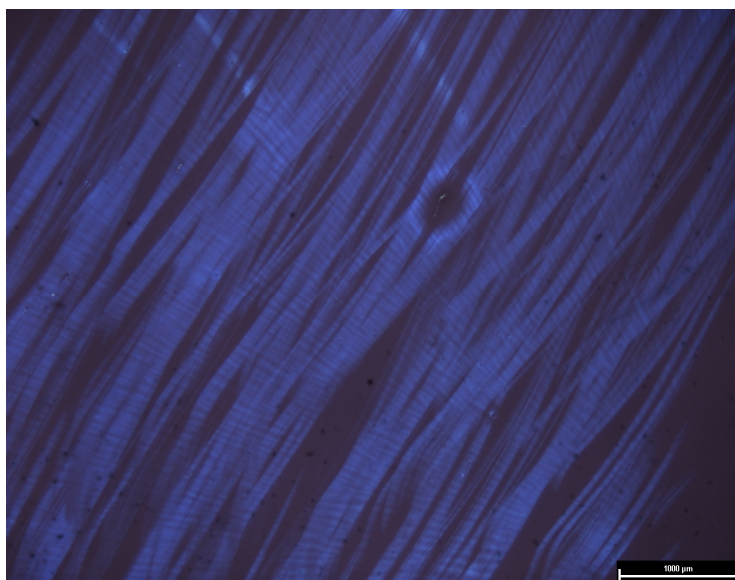


Figure ESI-19: PLM image of thin film cast from 8-1 blend after annealing in air for 60 minutes.

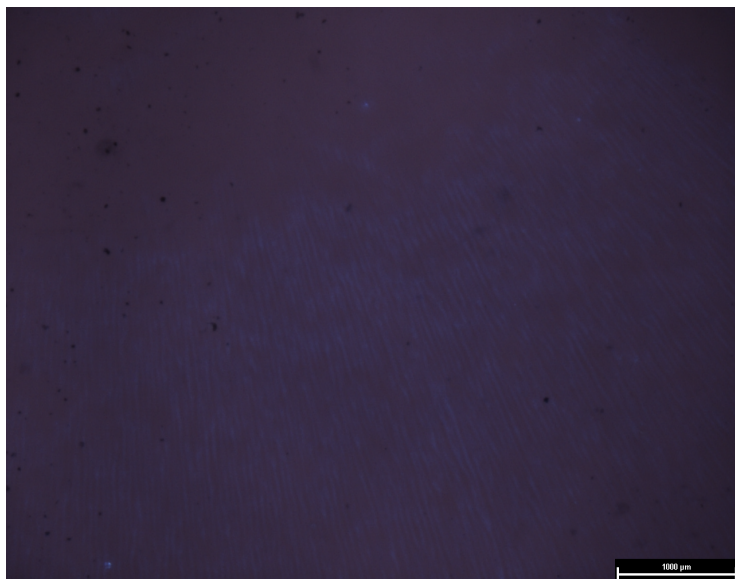


Figure ESI-20: PLM image of thin film cast from PFO after annealing in air for 60 minutes.

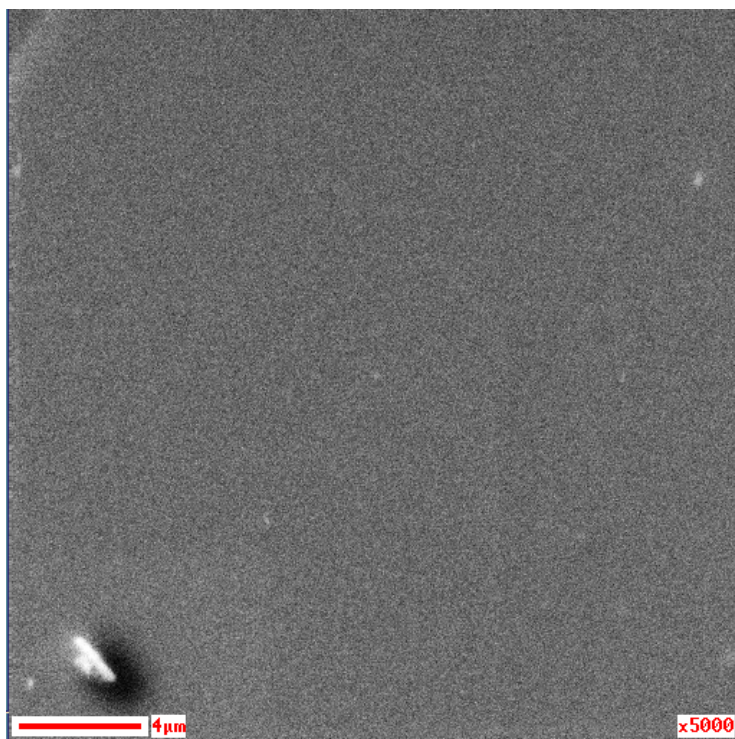


Figure ESI-21: SEM image of thin film cast from 1-1 blend.

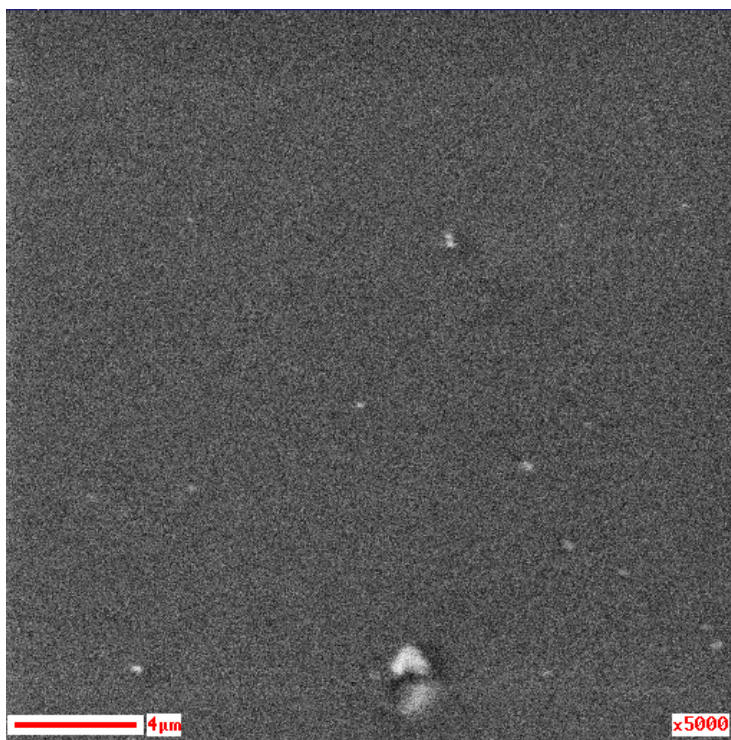


Figure ESI-22: SEM image of thin film cast from PFO.

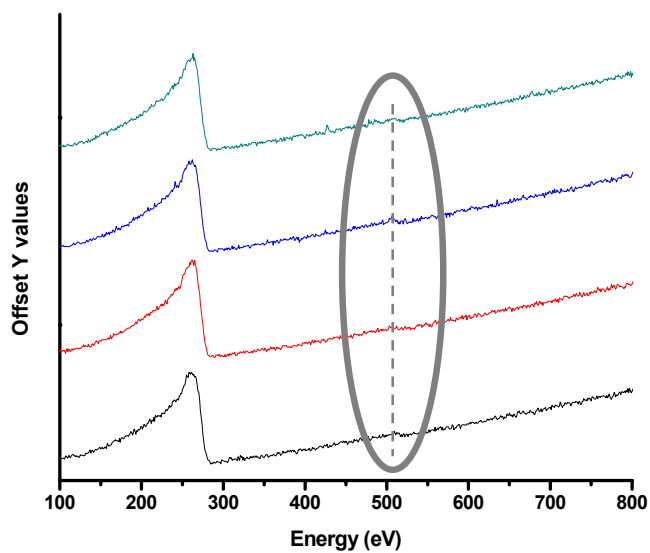


Figure ESI-23: Stacked AES spectra measured at four different points on thin film cast from 1-1 blend, showing carbon peak at ca. 260 nm, and a weak oxygen peak at ca. 510 nm (highlighted by the grey oval/dotted line).

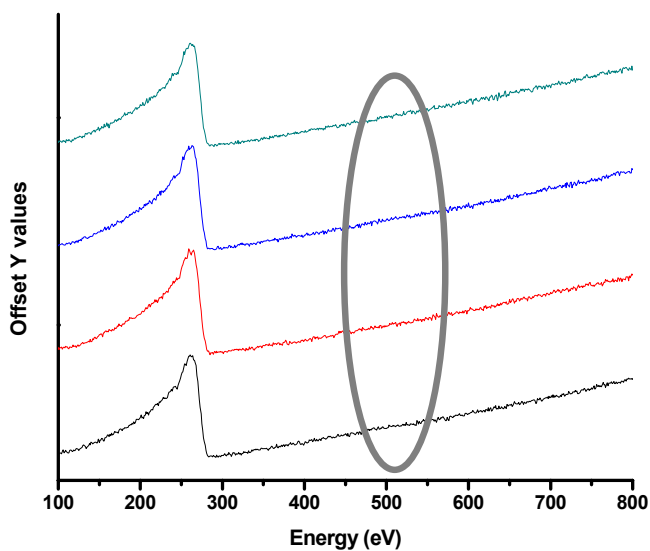


Figure ESI-24: Stacked AES spectra measured at four different points on thin film cast from PFO, showing a carbon peak at ca. 260 nm, and no oxygen peak (highlighted by the grey oval).

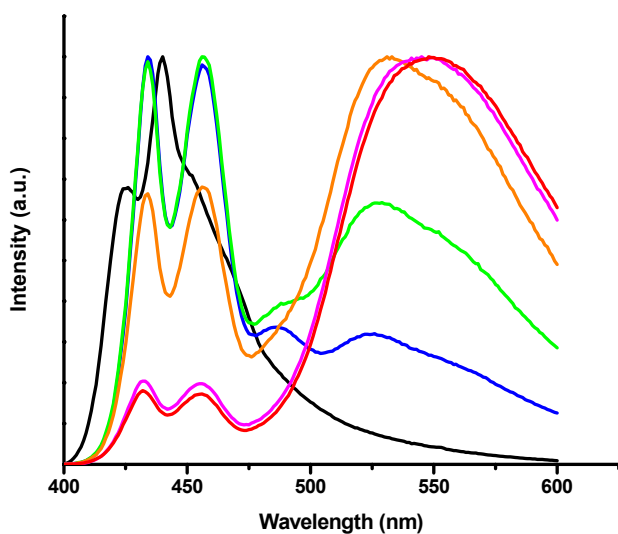


Figure ESI-25: Normalized photoluminescence spectra of a PFO thin film (ca. 100nm) measured prior to (black) and following annealing in air ($\lambda_{\text{ex}}=350\text{nm}$) for one hour (blue), three hours (green), five hours (orange), twenty-two hours (pink), and twenty-five hours (red).

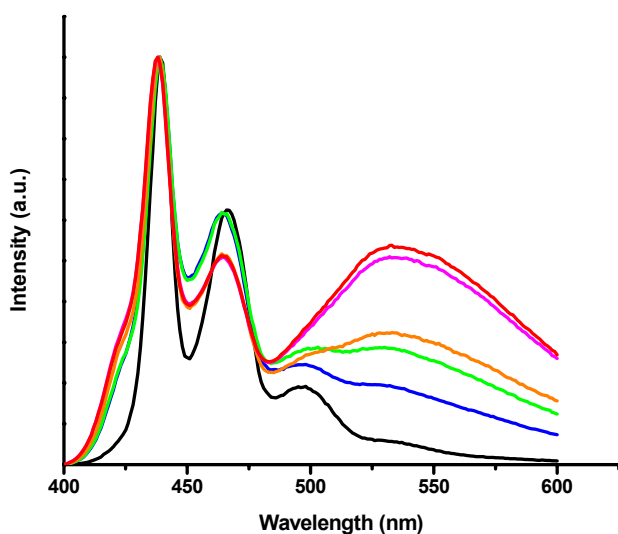


Figure ESI-26: Normalized photoluminescence spectra of a 1-1 blend thin film (ca. 100nm) measured prior to (black) and following annealing in air ($\lambda_{\text{ex}}=350\text{nm}$) for one hour (blue), three hours (green), five hours (orange), twenty-two hours (pink), and twenty-five hours (red).

PLED Fabrication and testing. Indium-tin oxide (ITO)-coated glass substrates (8-12 ohm/sq, Delta Technologies) were pre-cleaned by sonicating three times each in detergent (Sparkleen 1), distilled water, methanol, acetone and 2-propanol. The clean dry substrates were then exposed to an oxygen plasma using a Plasmalab MicroEtch RIE for one minute in preparation for deposition of a PEDOT:PSS layer. This layer was spin-coated using a Head-way resist spinner at 500 rpm for 5 seconds, followed by 1000 rpm for 10 seconds and finally 4000 rpm for 45 seconds. This thin film (ca. 60 nm) was annealed in air for ten minutes in a class 10 cleanroom at 60°C. The emissive layer was prepared by spin-coating either PFO or the 1-1 blend from CHCl_3 (using the same protocol described above). An aluminum cathode was subsequently thermally evaporated onto the organic layered structure in a vacuum deposition system located in a Nitrogen filled MBraun glovebox. Electroluminescent (EL) measurements were taken at 0.1 mA with a Gigahertz-Optik X4-OLED Light Analyzer, and a Varian Cary Eclipse Fluorescence Spectrophotometer; IV curves were recorded with a Gigahertz-Optik X4-OLED Light Analyzer. The current was measured as voltage was increased by 0.1 volts/step from 0 to 10 volts, holding for 0.5 seconds at each step.